

US Regional Update

- Intel - Data on contaminated optic in the MET (presentation later in this TWG session by Manish Chandhok)
- NIST-Intel
 - Continued studies to define critical elements in optics lifetime testing: new findings on non linear dependence of damage on dose and on H₂O partial pressures show how difficult it is to design accelerated test. See 6517-15 this SPIE Meeting
- Fraunhofer-Intel (See 6517-104 this SPIE meeting)
 - Proposed expansion of lifetime testing with pulsed source in collaboration with Albany
 - High values of reflectivity achieved with cap layers: RuO₂ greater than 67%; TiO₂ greater than 67.5.
- Albany - “Resist outgassing and its role in optics contamination” (presentation later in this TWG session by Greg Denbaeux)